



# Traceability North America TC Chapter

## Meeting Summary and Minutes

Wednesday, April 7, 2021

10:00 AM - 12:30 PM (Pacific Time)

OVTCCM

### TC Chapter Announcements

*Next TC Chapter Meeting*

July 28, 2021

10:00 AM - 12:30 PM Pacific

OVTCCM

### Table 1 Meeting Attendees

*Italics indicate virtual participants*

**Co-Chairs:** Yaw Obeng (NIST), Dave Huntley (PDF Solutions)

**SEMI Staff:** Michelle Sun (SEMI)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>BESI</i>	<i>Meusburger</i>	<i>Peter</i>	<i>Samsung</i>	<i>Bruce</i>	<i>Eric</i>
<i>GlobalFoundries</i>	<i>Hanan</i>	<i>Jeff</i>	<i>SCREEN</i>	<i>Nishimura</i>	<i>Takayuki</i>
<i>Lockheed Martin</i>	<i>Long</i>	<i>Ethan</i>	<i>SEMI</i>	<i>Sun</i>	<i>Michelle</i>
<i>Micron</i>	<i>Cicero</i>	<i>Jason</i>	<i>SEMI</i>	<i>Trio</i>	<i>Paul</i>
<i>Omron</i>	<i>Infelise</i>	<i>Nick</i>	<i>SumCryogenics</i>	<i>Apparao</i>	<i>Tamirisa</i>
<i>PEER Group</i>	<i>Fuchigami</i>	<i>Albert</i>			

### Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
5-Year Review Task Force	Yoshise Masanori (Self)	Emily Liew (XFab)

### Table 3 Committee Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	

### Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
6448	New Standard – Specification for Equipment and Materials Labels	<b>Failed</b>

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.



**Table 5 Activities Approved by the GCS between meetings of the TC Chapter**

#	Type	SC/TF/WG	Details
None			

**Table 6 Authorized Activities**

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	Type	SC/TF/WG	Details
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARE>

**Table 7 Authorized Ballots**

#	When	TF	Details
6448A	Cycle 4- or 5-2021	EMT TF	New Standard – Specification for Equipment and Materials Labels
6698	Cycle 4- or 5-2021	5-Year Review TF	Revision of SEMI M12-0706 (reapproved 0318), Specification for Serial Alphanumeric Marking of the Front Surface of Wafers, with title change to: Specification for Alphanumeric Marking of Wafers
6699	Cycle 4- or 5-2021	5-Year Review TF	Revision of SEMI M13-0706 (reapproved 0318), Specification for Alphanumeric Marking of Silicon Wafers (Subject: adding alphanumeric marking at back surface in addition to front surface.)

**Table 8 SNARF(s) Granted a One-Year Extension**

#	TF	Title	Expiration Date
None			

**Table 9 SNARF(s) Abolished**

#	TF	Title
None		

**Table 10 Standard(s) to receive Inactive Status**

Standard Designation	Title
None	

**Table 11 New Action Items**

Item #	Assigned to	Details
None		

**Table 12 Previous Meeting Action Items**

Item #	Assigned to	Details
None		



## 1 Welcome, Reminders, and Introductions

Yaw Obeng (NIST) called the meeting to order at 10:05. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

**Attachment:** Required Element Nov 2020 Rev1 (3)

## 2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

**Motion:** Approve the minutes as written  
**By / 2<sup>nd</sup>:** By: Nick Infelise / Omron Electronics, Inc  
Second: Albert Fuchigami / PEER Group Inc.  
**Discussion:** None  
**Vote:** 9-Y 0-N. Motion passed.

**Attachment:** NA-Traceability-TC-Chapter-Minutes-Feb-2021

## 3 Liaison Reports

### 3.1 Traceability Japan TC Chapter

Michelle Sun (SEMI) gave the liaison report. Of note:

- Last meeting
  - March 17, 2021
- Next meeting
  - Sometime in June
- The Blockchain TF submitted a request for approval of the Type 3 Liaison (ISO) at the committee meeting and the TC Chapter approved it.

**Attachment:** JA\_Trace\_Liaison\_2020329\_v1

### 3.2 SEMI Staff Report

Michelle Sun (SEMI) gave the SEMI Staff Report. Of note:

SEMI Global Calendar of Events

- SEMICON China (March 17-19, 2021; Shanghai, China)
- SEMICON Southeast Asia (May 18-20, 2021; Penang, Malaysia)
- SEMICON Taiwan (Sept 8-10, 2021; Taipei, Taiwan)
- SEMICON West (December 7-9, 2021; [Hybrid] San Francisco, CA)

Critical Dates for SEMI Standards Ballots

- Cycle 2-2021: Ballot Submission Due: Jan 29/Voting Period: Feb 10 – Mar 12
- Cycle 3-2021: Ballot Submission Due: Mar 9/Voting Period: Mar 23 – Apr 22
- Cycle 4-2021: Ballot Submission Due: Apr 14/Voting Period: Apr 28 – May 28
- Cycle 5-2021: Ballot Submission Due: May 18/Voting Period: June 1 – July 1
- Cycle 6-2021: Ballot Submission Due: Aug 3/Voting Period: Aug 17 – Sept 16
- Cycle 7-2021: Ballot Submission Due: Sept 1/Voting Period: Sept 15 – Oct 15
- Cycle 8-2021: Ballot Submission Due: Oct 8/Voting Period: Oct 22 – Nov 22
- Cycle 9-2021: Ballot Submission Due: Nov 16/Voting Period: Nov 30 – Dec 30

Critical Dates: <http://www.semi.org/en/Standards/Ballots>



## Standards Publications Report

Total in portfolio – 1,029 (includes 274 Inactive Standards)

<i>Cycle</i>	<i>New</i>	<i>Revised</i>	<i>Reapproved</i>	<i>Withdrawn</i>
November 2020	1	2	0	0
December 2020	1	3	3	0
January 2020	0	1	6	0

## New Standards

<i>Cycle</i>	<i>Designation</i>	<i>Title</i>	<i>Committee</i>	<i>Region</i>
November 2020	SEMI C100	Guide for Reporting Chemical Mechanical Planarization (CMP) Polishing Pads Hardness Used in Semiconductor Manufacturing	Liquid Chemicals	NA
December	SEMI PV97	Specification for Silicon Powder Used in Polysilicon Production	Photovoltaic	CH

## Inactive Standards

### *Number of Inactive Standards*

Assembly & Packaging	48
Automated Test Equipment	2
Compound Semiconductor Materials	4
Environmental Health & Safety	8
Facilities	15
FPD – Equipment	5
FPD – Factory Automation	14
FPD – Materials & Components	13
Gases	18
Information & Control	37
Liquid Chemicals	26
MEMS	3
Metrics	12
Micropatterning	30
Photovoltaic	1
Physical Interfaces & Carriers	19
Silicon Wafer	11
Traceability	8

## Regulations & Procedure Manual

- Regulations (November 5, 2020)
  - Clarification on § 6.5, Disbandment of a TC Chapter
  - Requires an RSC to disband a TC Chapter when it is shown to be inactive by failing to:
    - hold meetings for two consecutive years,
    - report activity to its RSC for two consecutive years, or
    - initiate new Standards Documents activities.
  - Procedure Manual (November 5, 2020)
  - New § 6.1.3.4.1 defining detailed procedures for disbandment of inactive TC Chapters.

Official Virtual TC Chapter Meeting Rooms {See attachment for additional slides}



- All Chapters of the PIC GTC have completed the simulation training of an Official Virtual TC Chapter Meeting (OVTCCM).
- Nonconforming Titles (See PM Appendix 4) *{None}*
- SNARF 3 Year Status, TC Chapter may grant a one-year extension *{None}*
- Five-Year Review

Display Name	Description	Date Available	Status
SEMI T9-1110 (Reapproved 0216)	Specification for Marking of Metal Lead-Frame Strips with a Two-Dimensional Data Matrix Code Symbol	2/5/2016	Reapproval ballot to be issued in Cycle 5-2021
SEMI T8-1110 (Reapproved 0216)	Specification for Marking of Glass Flat Panel Display Substrates with a Two-Dimensional Matrix Code Symbol	2/5/2016	Reapproval ballot to be issued in Cycle 5-2021
SEMI T7-0516	Specification for Back Surface Marking of Double-Side Polished Wafers with a Two-Dimensional Matrix Code Symbol	5/13/2016	Reapproval ballot to be issued in Cycle 5-2021
SEMI T5-1214	Specification for Alphanumeric Marking of Round Compound Semiconductor Wafers	12/5/2014	Revision underway
SEMI T20-0710 (Reapproved 0416)	Specification for Authentication of Semiconductors and Related Products	4/22/2016	Reapproval ballot to be issued in Cycle 5-2021
SEMI T16-0310 (Reapproved 0216)	Specification for Use of Data Matrix Symbology for Automated Identification of Extreme Ultraviolet Lithography Masks	2/19/2016	Reapproval ballot to be issued in Cycle 5-2021
SEMI T11-0703 (Reapproved 1014)	Specification for Marking of Hard Surface Reticle Substrates	10/30/2014	Re-approved

**Attachment:** Staff Report Feb 2021\_v3

#### 4 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

##### 4.1 Document #6448, New Standard – Specification for Equipment and Materials Labels

**Motion:** Negative from Supika Mashiro is related and persuasive.  
**By / 2<sup>nd</sup>:** By: Albert Fuchigami / PEER Group Inc.  
 Second: Takayuki Nishimura / SCREEN Semiconductor Solution Co., Ltd.  
**Discussion:** None.  
**Vote:** 8-Y 0-N. Motion passed.

**Motion:** This Document failed TC Chapter review and will be returned to the TF for rework.



**By / 2<sup>nd</sup>:** By: Albert Fuchigami / PEER Group Inc.  
Second: Takayuki Nishimura / SCREEN Semiconductor Solution Co., Ltd.  
**Discussion:** None.  
**Vote:** 9-Y 0-N. Motion passed.

## 5 Subcommittee and Task Force Reports

### 5.1 Equipment and Materials Traceability (EMT) Task Force

Albert Fuchigami (PEER Group) reported for the EMT Task Force. Of note:

- Ballot 6448 - Equipment and Materials Labels
  - Reviewed Cycle 2 ballot feedback and comments
  - Look at if we need to include an example of a part that does not need a MAT Label (\$0.01 resistor may need a label if customer needs traceability for it).
  - Repair Kits – may have a MAT Label, but parts inside may also have a MAT Label – depend if parts are under serialized control. VDA Field can be used to store custom information – use to store Kit ID.  
Look at adding Related Information use case for kits – MAT Label for the kit and MAT Label for a part in the kit.
- Ballot 6449 - Equipment and Materials Part Traceability
  - Q – will Blockchain will not be part of this standard?  
A – No. Initial targeted implementation technology (RosettaNet, XML, CSV) do not support this technology If there is a need in the future, can look at creating a new subordinate standard to implement.

**Attachment:** EMT TF April 2021 Report\_Rev 1.0

### 5.2 Single Device Traceability (SDT) Task Force

Michelle Sun (SEMI) reported for the SDT Task Force. Of note:

- GSA-TIES liaison approved. SDT TF has begun collaboration with GSA-TIES to further the development of Doc. 6504.

**Attachment:** SDT TF Meeting\_03082021\_v1

## 6 Old Business

None.

## 7 New Business

None.

## 8 Next Meeting and Adjournment

The next meeting is scheduled for July 28, 2021, from 10:00 AM - 12:30 PM Pacific via Online Conference. See <http://www.semi.org/standards-events> for the current list of events.

Respectfully submitted by:

Michelle Sun



Coordinator  
SEMI North America  
Phone: 408.943.7982  
Email: msun@semi.org

Minutes tentatively approved by:

Yaw Obeng, Co-chair	5/12/2021
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**Table 13 Index of Available Attachments<sup>#1</sup>**

<i>Title</i>	<i>Title</i>
Required Element Nov 2020 Rev1 (3)	SDT TF Meeting_03082021_v1
NA-Traceability-TC-Chapter-Minutes-Feb-2021	JA_Trace_Liaison_2020329_v1
Staff Report Feb 2021_v3	
EMT TF April 2021 Report_Rev 1.0	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at [www.semi.org](http://www.semi.org). For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.